

Examiner-Initiated Interview Summary	Application N .	Applicant(s)	
	10/698,632	MORRIS ET AL.	
	Examiner	Art Unit	
	Akm Enayet Ullah	2874	

All Participants:

(1) Akm Enayet Ullah.

(2) Susan S. Morse (Reg.no. 35,292).

Date of Interview: 21 June 2004

Type of Interview:

☒ Telephonic
☐ Video Conference
☐ Personal (Copy given to: ☐ Applicant ☒ Applicant's representative)

Exhibit Shown or Demonstrated: ☐ Yes ☒ No
 If Yes, provide a brief description:

Status of Application: _____

(3) _____

(4) _____

Time: _____

Part I.

Rejection(s) discussed:
 NONE

Claims discussed:
 1-27

Prior art documents discussed:
 Japanese Patent # JP 05008441 A (Kyocera Corp) and USPatent no. 5,444,572 A)


Part II.

SUBSTANCE OF INTERVIEW DESCRIBING THE GENERAL NATURE OF WHAT WAS DISCUSSED:
 See Continuation Sheet

Part III.

☒ It is not necessary for applicant to provide a separate record of the substance of the interview, since the interview directly resulted in the allowance of the application. The examiner will provide a written summary of the substance of the interview in the Notice of Allowability.

☐ It is not necessary for applicant to provide a separate record of the substance of the interview, since the interview did not result in resolution of all issues. A brief summary by the examiner appears in Part II above.


AKM ENAYET ULLAH
PRIMARY EXAMINER

(Examiner/SPE Signature)

(Applicant/Applicant's Representative Signature – if appropriate)

Continuation of Substance of Interview including description of the general nature of what was discussed: Two (2) ways restriction was made in this application. Group I, claims 1-11 and Group II, claims 12- 27. Applicant's attorney elected without traverse Group I, claims 1-11 for the examination purpose. Claims 1-11 are allowable over the prior art as of record..



AKM ENAYET ULLAH
PRIMARY EXAMINER

Reasons For Allowance

None of the reference disclose alone or in combination an array of micro-optical components wherein at least one corresponding compensation feature and at least two surfaces of the array of micro-optical components being different from one another, wherein at least two combinations of refractive surfaces and corresponding compensation surfaces operate at different focal lengths components


**AKM ENAYET ULLAH
PRIMARY EXAMINER**

*Restriction to one of the following inventions is required
under 35 U.S.C. 121:*

- I. Claims 1-11, drawn to an array of micro-optical components, classified in class 385, subclass 147.
- II. Claims 12- 27, drawn to a method of forming micro-optical components, classified in class 65, subclass 385.

The inventions are distinct, each from the other because:

Inventions II and I are related as process of making and product made. The inventions are distinct if either or both of the following can be shown: (1) that the process as claimed can be used to make other and materially different product or (2) that the product as claimed can be made by another and materially different process (MPEP § 806.05(f)). In the instant case Group I and Group II are related as process of making and product made. The inventions are distinct if either or both of the following can be shown: (1) that the process as claimed can be used to make other and materially different product or (2) that the product as claimed can be made by another and materially different process (MPEP § 806.05(f)). In the instant case, rather than etching, selective deposition of material can be used to form the compensation features.

Because these inventions are distinct for the reasons given above and have acquired a separate status in the art as shown by their different classification, restriction for examination purposes as indicated is proper.

Because these inventions are distinct for the reasons given above and have acquired a separate status in the art because of their recognized divergent subject matter, restriction for examination purposes as indicated is proper.

Because these inventions are distinct for the reasons given above and the search required for Group I is not required for Group II, restriction for examination purposes as indicated is proper.

Applicant is reminded that upon the cancellation of claims to a non-elected invention, the inventorship must be amended in compliance with 37 CFR 1.48(b) if one or more of the currently named inventors is no longer an inventor of at least one claim remaining in the application. Any amendment of inventorship must be accompanied by a request under 37 CFR 1.48(b) and by the fee required under 37 CFR 1.17(i).


During a telephone conversation with Ms. Susan S. Morse (Reg.no. 35,292) on June 21, 2004 a provisional election was made without traverse to prosecute the invention of Group I, claims 1-11. Affirmation of this election must be made by applicant in replying to this Office action. Claims 12-27 are withdrawn from further consideration by the examiner, 37 CFR 1.142(b), as being drawn to a non-elected invention.

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Akm Enayet Ullah whose telephone number is 571-272-2361. The examiner can normally be reached on Monday through Wednesday from 5:30 am to 6:30 p.m.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Rodney Bovernick, can be reached on 571-272-2344. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).


Akm Enayet Ullah
Primary Examiner
Art Unit 2874

AULLAH